

Notice of References Cited	Application/Control No. 10/814,723		Applicant(s)/Patent Under Reexamination OFEK ET AL.	
	Examiner TAN TRINH		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,969,689	10-1999	Martek et al.	343/758
*	B	US-2004/0196834	10-2004	Ofek et al.	370/352
*	C	US-6,683,567	01-2004	De Champlain et al.	342/385
*	D	US-2003/0043071	03-2003	Lilly et al.	342/368
*	E	US-2002/0058503	05-2002	Gutowski, Stan J.	455/423
*	F	US-6,587,080	07-2003	De Champlain et al.	342/450
*	G	US-2004/0185825	09-2004	Preiss et al.	455/405
*	H	US-2003/0045229	03-2003	Snelgrove et al.	455/3.05
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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